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## Latent Damage and Reliability in Semiconductor Devices

**Advisor:** Dr. Randall Geiger

**Client:** Dr. Randall Geiger, EcpE

**Members (roles):**

Sean Santella (Leader)

Jaehyuk Han (Webmaster)

Hayle Olson (Communication Leader)

David Ackerman (Key Concept Holder)

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### **Weekly Summary:**

This week we had a second meeting with our team and Advisor. We continued researching articles and papers on our topic. We honed in our search efforts to focus on CMOS devices.

### **Meeting Notes:**

Advisor/Client Meeting (Sept. 9<sup>th</sup>)

*Duration:* 1 Hour

*Members Present:* Dr. Geiger, Sean Santella, Jaehyuk Han, Hayle Olson, David Ackerman

*Notes:* This meeting was held with Dr. Geiger to discuss our findings from our research the previous week. In this meeting we developed a better understanding of what we need to be looking for within our research.

### **Weekly Accomplishments:**

We researched articles and papers that were both for and against latent damage within CMOS devices. We also researched how to test for latent damage within these devices.

### **Plans for Next Week:**

- Continue research on latent damage within CMOS devices
- Continue research on testing for latent damage
- Start developing our website
- Start thinking about a project plan

### **Pending Issues:**

We currently do not have any pending issues.

**Individual Contributions:**

Sean Santella: Attended lecture and weekly advisor/client meeting.

Jaehyuk Han: Attended lecture and weekly advisor/client meeting.

Hayle Olson: Attended lecture and weekly advisor/client meeting, wrote weekly report, and researched related articles and papers.

David Ackerman: Attended lecture and weekly advisor/client meeting.

**Hourly Contributions:**

<u>Member:</u>	<u>Weekly Hours:</u>	<u>Total Hours:</u>
Sean Santella	2.0	4.5
Jaehyuk Han	2.0	4.5
Hayle Olson	2.5	5.0
David Ackerman	2.0	4.5